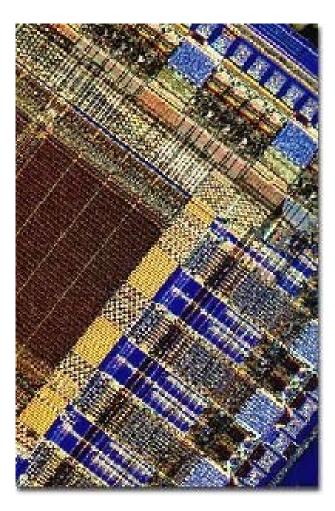
Digital Integrated Circuit Design and Architecture



Chapter 2: Fabrication of MOSFETs

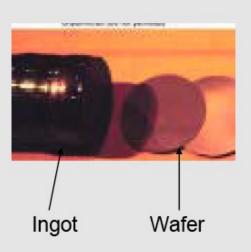
CMOS ICs Fabrication

- CMOS transistors and CMOS ICs are fabricated on silicon wafers
- Photo-Lithography process is used for the fabrication and it is similar to printing press
- On each step of different materials are deposited or etched

Silicon Ingot

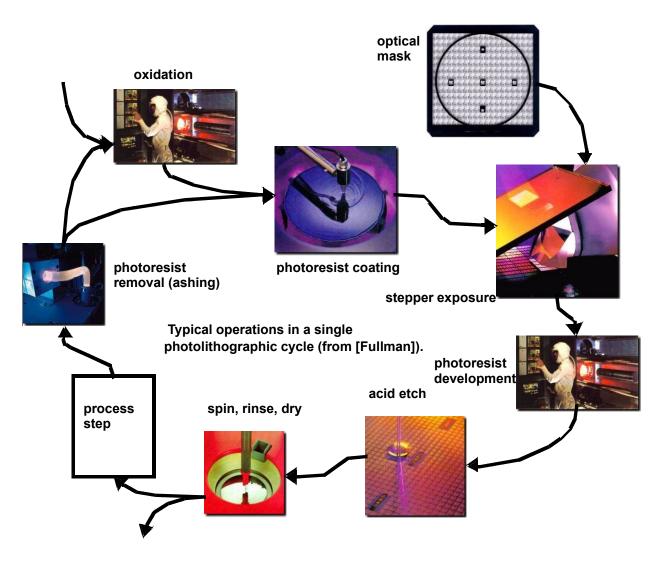
Silicon Ingot and Wafer Manufacturing



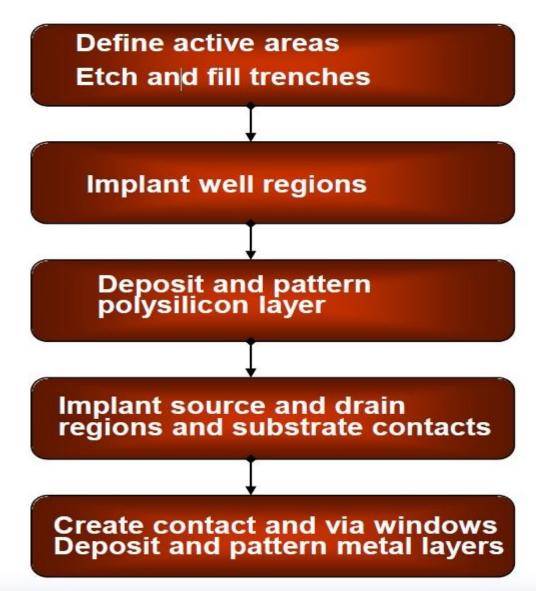


From Smithsonian, 2000

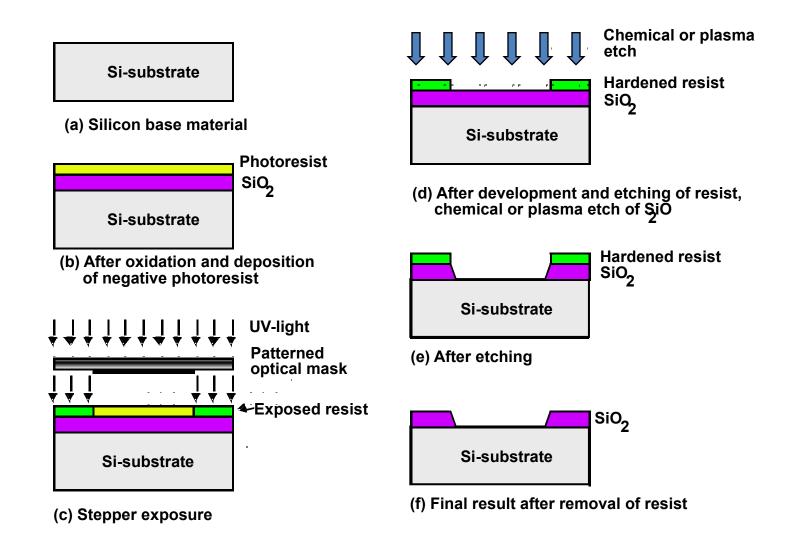
Photo-Lithographic Process



CMOS Process insight



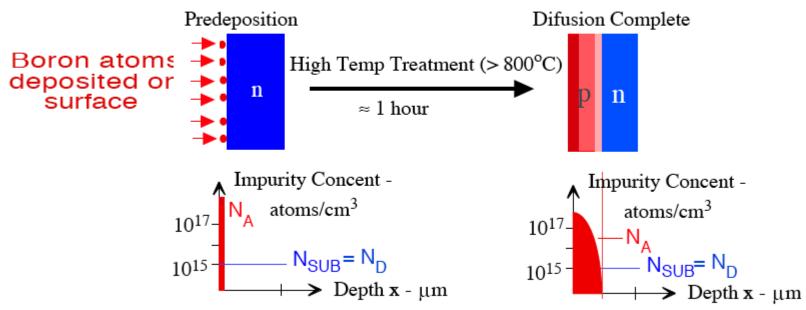
Patterning of SiO2 – Basic Steps



Creating Diffusion Regions

CMOS PROCESSING TECHNOLOGY

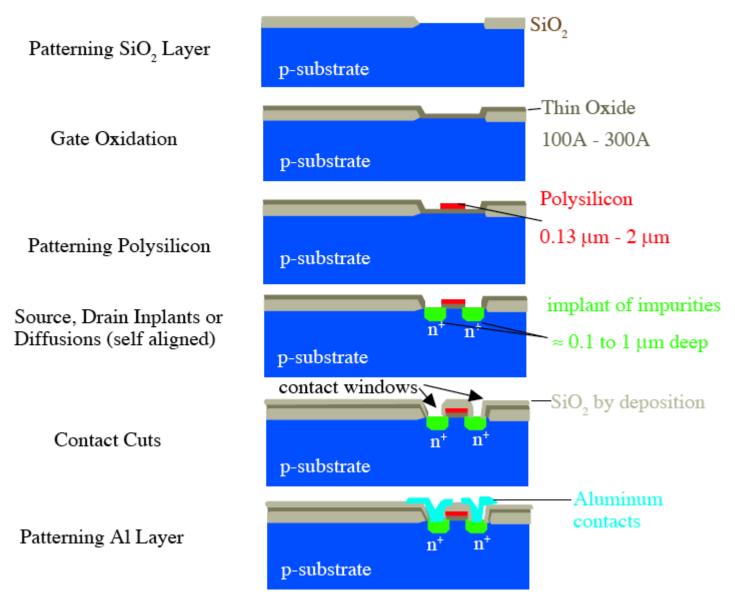
DIFFUSION PROCESS



-> Boron typically used for p-type doping

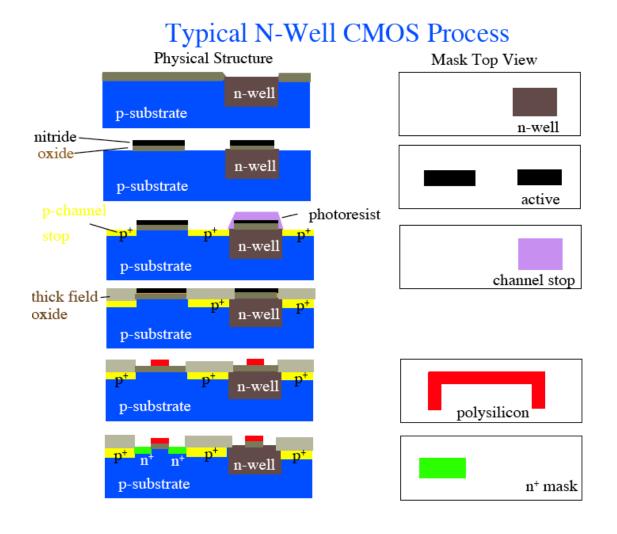
-> Arsenic and Phosphorus are typically used for n-type doping.

Fabrication Steps in Si-Gate (self-aligned) NMOS Process

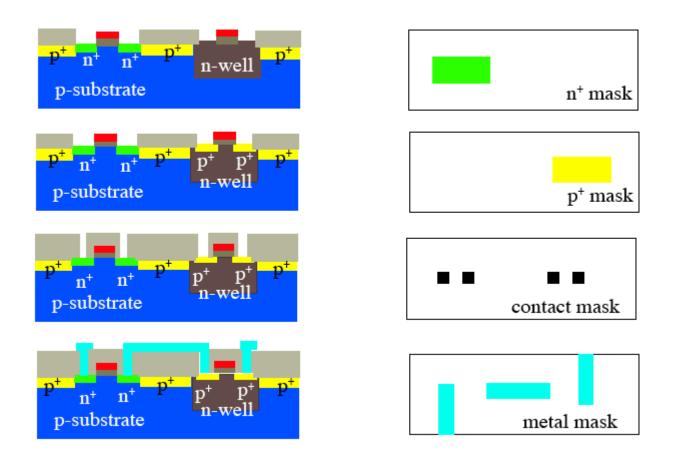


CMOS Process Walk-Through

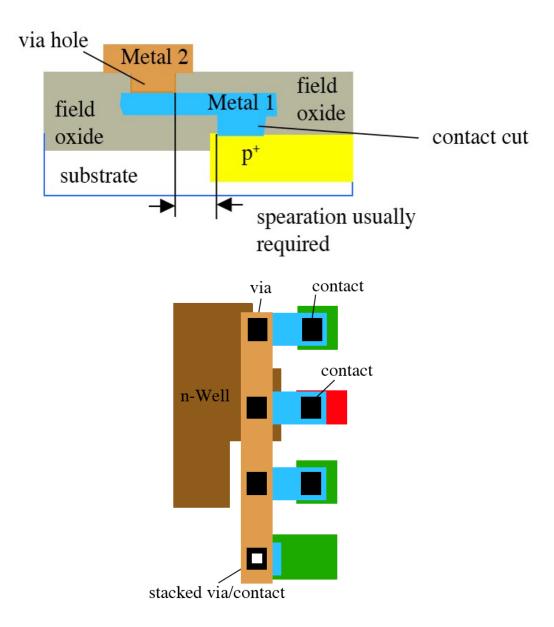
Fabrication of nMOS and pMOS transistors process example



CMOS Process Walk-Through



Contacts and Vias in CMOS Fabrication

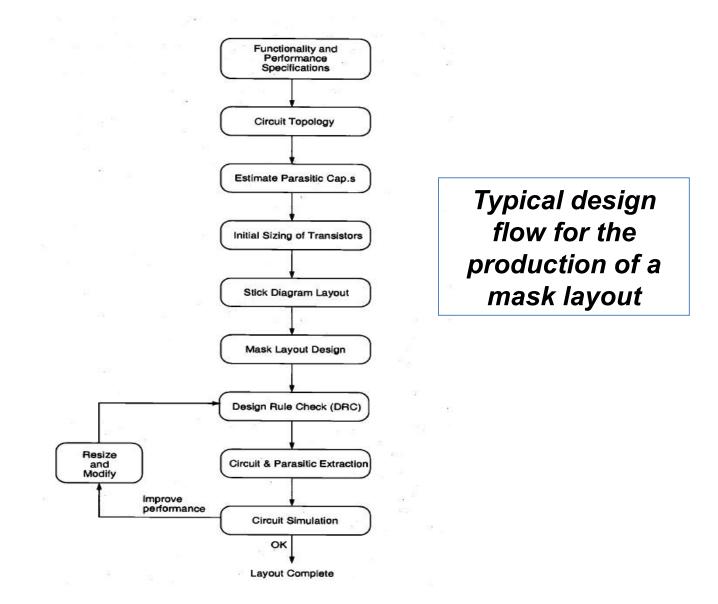


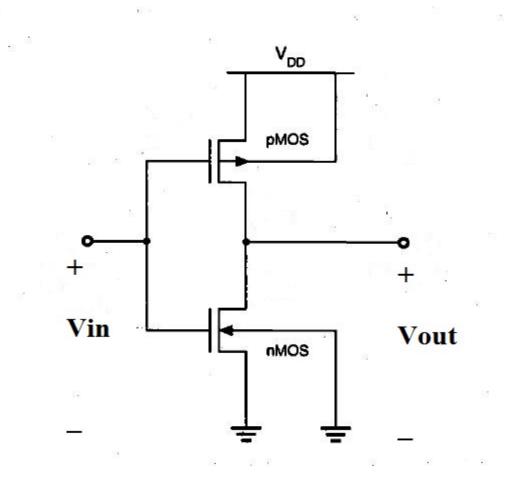
MOSIS (MOS Implementation) layout design rules

Rule num	ber Description	<i>ä</i>	λ -Rule
. 3	Active area rules		
R1	Minimum active area width		3λ
R2	Minimum active area spacing		3λ
	Polysilicon rules	672	
R3	Minimum poly width		2λ
R4 .	Minimum poly spacing		2λ
R5	Minimum gate extension of poly over active		2λ
R6	Minimum poly-active edge spacing		1λ
	(poly outside active area)		
R7	Minimum poly-active edge spacing		3λ
	(poly inside active area)		
	Metal rules		
R 8	Minimum metal width		3λ
R9	Minimum metal spacing		3λ
	Contact rules	25	
R10	Poly contact size		2λ
R11	Minimum poly contact spacing		2λ
R12	Minimum poly contact to poly edge spacing		1λ
R13	Minimum poly contact to metal edge spacing		1λ
R14	Minimum poly contact to active edge spacing		3λ
R15	Active contact size		2λ
R16	Minimum active contact spacing		2λ
	(on the same active region)		
R17	Minimum active contact to active edge spacing	21	1λ
R18	Minimum active contact to metal edge spacing		1λ
R19	Minimum active contact to poly edge spacing		3λ
R20	Minimum active contact spacing		6λ
	(on different active regions)		

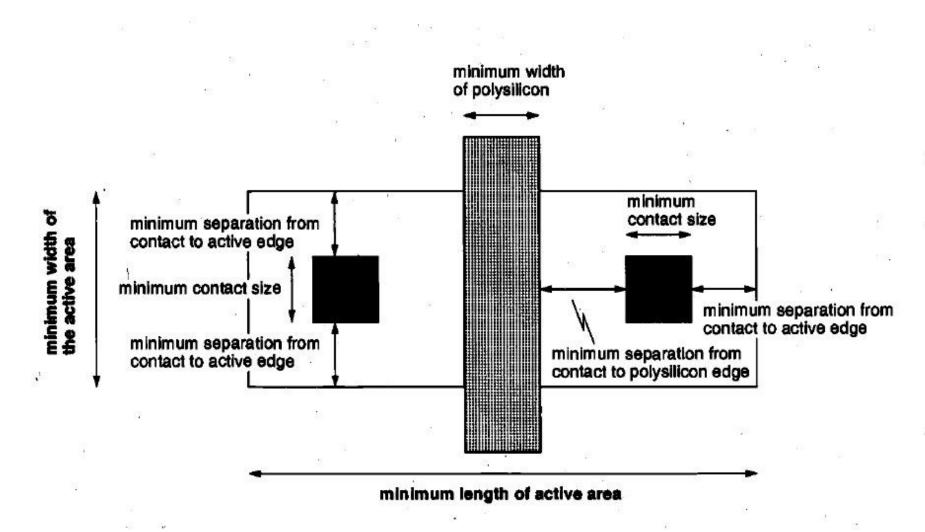
MOSIS (MOS Implementation) layout design rules

Rule number	Description	λ -Rule	R9
2 ji	Active area rules		R12
R1	Minimum active area width	3λ	
R2	Minimum active area spacing	3λ	
		(20) III	
	Polysilicon rules		
R3	Minimum poly width	2λ	R10 R1 R2 R20
R4 .	Minimum poly spacing	2λ	
R5	Minimum gate extension of poly over active	2λ	B13 .
R6	Minimum poly-active edge spacing	1λ	R5
	(poly outside active area)		R19
R7	Minimum poly-active edge spacing	3λ	
	(poly inside active area)		
	Metal rules		R7 R7
R8	Minimum metal width	3λ	
R9	Minimum metal spacing	3λ	R3
			R8
	Contact rules	20	
R10	Poly contact size	2λ	
R11	Minimum poly contact spacing	2λ	
R12	Minimum poly contact to poly edge spacing	1λ	
R13	Minimum poly contact to metal edge spacing	1λ	
R14	Minimum poly contact to active edge spacing	3λ	
11 Paris	11	200 D	Active area
R15	Active contact size	2λ	
R16	Minimum active contact spacing	2λ	Polysilicon
	(on the same active region)		
R17	Minimum active contact to active edge spacing	1λ	
R18	Minimum active contact to metal edge spacing	1λ	Contact
R19	Minimum active contact to poly edge spacing	32	
R20		0A	Metal
R20	Minimum active contact spacing (on different active regions)	6λ	Metal

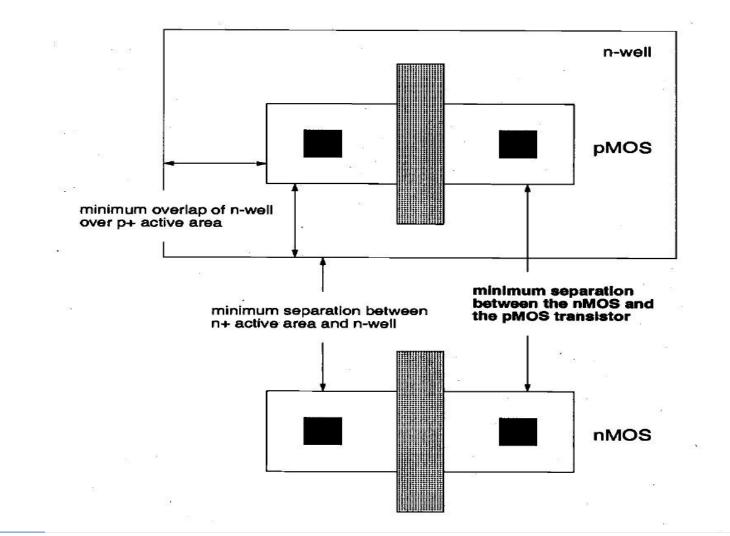




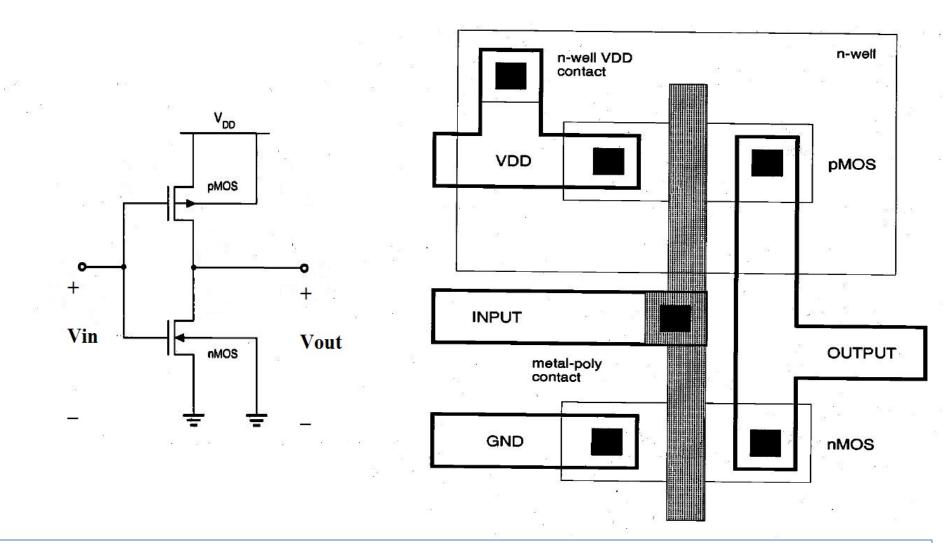
CMOS inverter



Design rules which determine the dimensions of a min size transistor



Design rules which determine the separation between nMOS and pMOS transistor



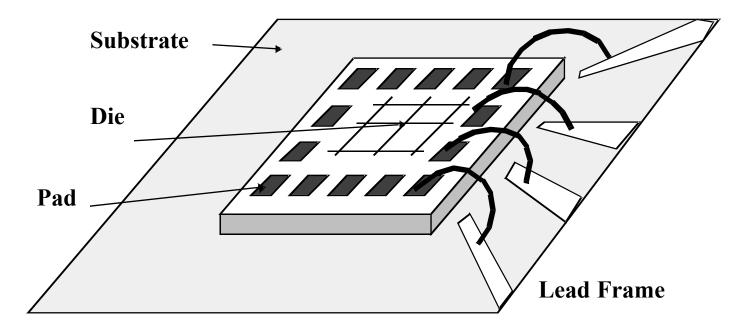
Complete mask layout of the CMOS inverter

Packaging Requirements

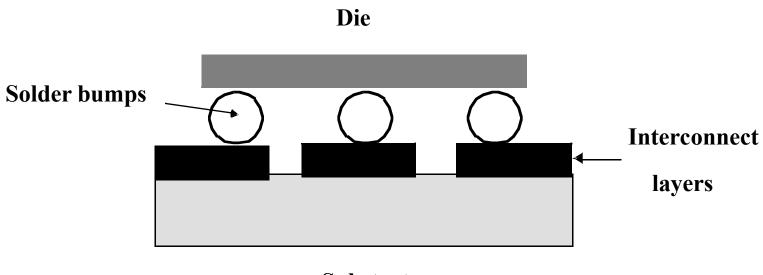
- Electrical: Low parasitics
- Mechanical: Reliable and robust
- Thermal: Efficient heat removal
- Economical: Cheap

Bonding Techniques

Wire Bonding

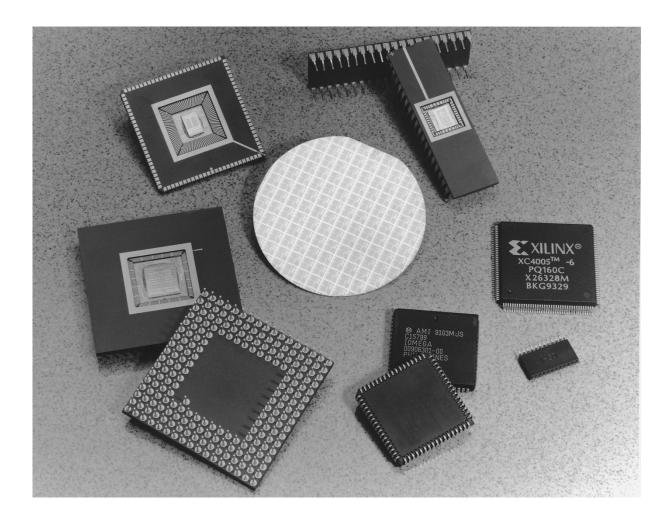


Flip-Chip Bonding



Substrate

Package Types



Package Parameters

Package Type	Capacitance (pF)	Inductance (nH)
68 Pin Plastic DIP	4	35
68 Pin Ceramic DIP	7	20
256 Pin Pin Grid Array	5	15
Wire Bond	1	1
Solder Bump	0.5	0.1

Typical Capacitances and Inductances of Various Package and Bonding Styles (from [Sze83])